

SERESSA 2025

연사소개



Raoul Velazco

Université Joseph Fourier (UJF), France
Error rate prediction for programmable circuits: methodology, tools, and studied cases



Ricardo Augustro Da Luz Reis

Federal University of Rio Grande do Sul (UFRGS), Brazil

Mitigation of Soft Errors at Circuit Level



Dale McMorrow

US Naval Research Laboratory, Washington DC, USA
Surrogate Test Approaches: Enabling Capabilities for Predictive Testing Using Pulsed Lasers and Other Methods



Insoo Jun

The Jet Propulsion Laboratory, California Institute of Technology, USA
Space Radiation Challenges for deep Space Missions in the Artemis Era: Moon to Mars



Sanghyun Baek

Professor, Hanyang University, Republic of Korea
Radiation Effects During X-ray PCB Inspection



Ennio Tito Capria

Deputy Head of Business Development European Synchrotron (ESRF), France
How synchrotron light sources can help to overcome the major limitations related to Heavy Ions Single Event Effects testing in electronic circuits



Juan Antonio Clemente

Complutense University of Madrid (UCM), Spain

LELAPE: An open-source tool to classify SEUs according to their multiplicity in radiation-ground tests on memories



Pablo Alejandro Ferreyra

National University of Córdoba (UNC), Argentina
Systems On Chips based Ionizing Radiation Robustness



Viyas Gupta

ESA/ESTEC, European Space Agency, The Netherlands
ESA Mission Classification: focus on RHA tailoring & recommendations for COTS projects



Masanori Hashimoto

Professor Masanori Hashimoto, Ph. D., Osaka University, Japan
Impact of Irradiation Side on MuonInduced Single Event Upsets in 65-nm Bulk SRAMs



Corinna Martinella

ETH Zurich, Postdoctoral Researcher and Lecturer, Switzerland
Radiation effects in wide-bandgap power devices: single event effects and total ionizing dose in SiC and GaN technologies



Otmane Ait Mohamed

ECE Department, Concordia University, Montreal, Canada
Single Event Multiple Transient Analysis of Digital Circuits using Satisfiability Modulo Theories



Luca Sterpone

Full Professor of Computer Engineering DAUIN - Politecnico di Torino Politecnico di Torino, Italy
SEE effects on VLSI devices: challenges and solutions



Cher Ming Tan

Director, Center for Reliability Sciences and Technologies, Chang Gung University, Taiwan
Radiation Reliability for Electronics, from System to Components



Jae-Sung Yun

University of Surrey, Guildford, United Kingdom
Enhancing Radiation Tolerance of Halide Perovskite Solar Cells for Space Applications